

| | | | | |
|-----------------------------------|---------------------------------------|--|---------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 10/716,464 | | Applicant(s)/Patent Under Reexamination FUJIWARA ET AL. | |
| | Examiner Xavier Szewai Wong | | Art Unit 2416 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------------|----------------|
| * | A | US-6,263,211 | 07-2001 | Brunner et al. | 455/464 |
| * | B | US-5,956,331 | 09-1999 | Rautiola et al. | 370/338 |
| * | C | US-7,274,782 B2 | 09-2007 | Forte, Stephen P. | 379/201.01 |
| * | D | US-6,122,502 | 09-2000 | Grundvig et al. | 455/414.1 |
| * | E | US-7,039,401 B2 | 05-2006 | Eynard et al. | 455/433 |
| * | F | US-6,920,318 B2 | 07-2005 | Brooking et al. | 455/419 |
| * | G | US-7,003,287 B2 | 02-2006 | Roeder, G. R. Konrad | 455/417 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.